



## Features

- 3rd generation SiC MOSFET technology
- Optimized package with separate driver source pin
- High blocking voltage with low on-resistance
- High-speed switching with low capacitances
- Fast intrinsic diode with low reverse recovery ( $Q_{rr}$ )
- Halogen free, RoHS compliant

$V_{DS}$	650 V
$I_D @ 25^\circ C$	37 A
$R_{DS(on)}$	60 mΩ



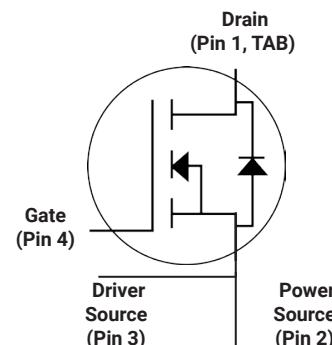
## Benefits

- Higher system efficiency
- Reduced cooling requirements
- Increased power density
- Increased system switching frequency
- Easy to parallel and simple to drive
- Enable new hard switching PFC topologies (Totem-Pole)

## Applications

- EV charging
- Server power supplies
- Solar PV inverters
- UPS
- DC/DC converters

Part Number	Package	Marking
HMM40N65T4	TO-247-4	HMM40N65T4 XXXX



## Maximum Ratings

Symbol	Parameter	Value	Unit	Note
$V_{DSS}$	Drain - Source Voltage, $T_c = 25^\circ C$	650	V	
$V_{GS}$	Gate - Source voltage (Under transient events < 100 ns)	-8/+19	V	Fig. 29
$I_D$	Continuous Drain Current, $V_{GS} = 15 V$ , $T_c = 25^\circ C$	37	A	Fig. 19
	Continuous Drain Current, $V_{GS} = 15 V$ , $T_c = 100^\circ C$	27		
$I_{D(pulse)}$	Pulsed Drain Current, Pulse width $t_p$ limited by $T_{jmax}$	99	A	
$P_D$	Power Dissipation, $T_c=25^\circ C$ , $T_j = 175^\circ C$	150	W	Fig. 20
$T_J$ , $T_{stg}$	Operating Junction and Storage Temperature	-40 to +175	°C	
$T_L$	Solder Temperature, 1.6mm (0.063") from case for 10s	260	°C	
$M_d$	Mounting Torque, (M3 or 6-32 screw)	1 8.8	Nm lbf-in	

**Electrical Characteristics** ( $T_c = 25^\circ\text{C}$  unless otherwise specified)

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions	Note
$V_{(\text{BR})\text{DSS}}$	Drain-Source Breakdown Voltage	650			V	$V_{\text{GS}} = 0 \text{ V}, I_D = 100 \mu\text{A}$	
$V_{\text{GS}\text{on}}$	Gate-Source Recommended Turn-On Voltage		15		V	Static	Fig. 29
$V_{\text{GS}\text{off}}$	Gate-Source Recommended Turn-Off Voltage		-4		V		
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	1.8	2.3	3.6	V	$V_{\text{DS}} = V_{\text{GS}}, I_D = 5 \text{ mA}$	Fig. 11
			1.9		V	$V_{\text{DS}} = V_{\text{GS}}, I_D = 5 \text{ mA}, T_J = 175^\circ\text{C}$	
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current		1	50	$\mu\text{A}$	$V_{\text{DS}} = 650 \text{ V}, V_{\text{GS}} = 0 \text{ V}$	
$I_{\text{GSS}}$	Gate-Source Leakage Current		10	250	nA	$V_{\text{GS}} = 15 \text{ V}, V_{\text{DS}} = 0 \text{ V}$	
$R_{\text{DS}(\text{on})}$	Drain-Source On-State Resistance	42	60	79	$\text{m}\Omega$	$V_{\text{GS}} = 15 \text{ V}, I_D = 13.2 \text{ A}$	Fig. 4, 5,6
			80			$V_{\text{GS}} = 15 \text{ V}, I_D = 13.2 \text{ A}, T_J = 175^\circ\text{C}$	
$g_{\text{fs}}$	Transconductance		10		S	$V_{\text{DS}} = 20 \text{ V}, I_{\text{DS}} = 13.2 \text{ A}$	Fig. 7
			9			$V_{\text{DS}} = 20 \text{ V}, I_{\text{DS}} = 13.2 \text{ A}, T_J = 175^\circ\text{C}$	
$C_{\text{iss}}$	Input Capacitance		1020		pF	$V_{\text{GS}} = 0 \text{ V}, V_{\text{DS}} = 600 \text{ V}$ $f = 1 \text{ MHz}$ $V_{\text{AC}} = 25 \text{ mV}$	Fig. 17, 18
$C_{\text{oss}}$	Output Capacitance		80				
$C_{\text{rss}}$	Reverse Transfer Capacitance		9				
$C_{\text{o(er)}}$	Effective Output Capacitance (Energy Related)		95		pF	$V_{\text{GS}} = 0 \text{ V}, V_{\text{DS}} = 0 \text{ V to } 400 \text{ V}$	Note 1
$C_{\text{o(tr)}}$	Effective Output Capacitance (Time Related)		132				
$E_{\text{oss}}$	$C_{\text{oss}}$ Stored Energy		15		$\mu\text{J}$	$V_{\text{DS}} = 600 \text{ V}, 1 \text{ MHz}$	Fig. 16
$E_{\text{ON}}$	Turn-On Switching Energy (Body Diode)		70		$\mu\text{J}$	$V_{\text{DS}} = 400 \text{ V}, V_{\text{GS}} = -4 \text{ V}/15 \text{ V}, I_D = 13.2 \text{ A}, R_{\text{G(ext)}} = 2.5 \Omega, L = 135 \mu\text{H}, T_J = 175^\circ\text{C}$ FWD = Internal Body Diode of MOSFET	Fig. 25
$E_{\text{OFF}}$	Turn Off Switching Energy (Body Diode)		5				
$E_{\text{ON}}$	Turn-On Switching Energy (External SiC Diode)		67				
$E_{\text{OFF}}$	Turn Off Switching Energy (External SiC Diode)		6		$\mu\text{J}$	$V_{\text{DS}} = 400 \text{ V}, V_{\text{GS}} = -4 \text{ V}/15 \text{ V}, I_D = 13.2 \text{ A}, R_{\text{G(ext)}} = 2.5 \Omega, L = 135 \mu\text{H}, T_J = 175^\circ\text{C}$ FWD = External SiC Diode	Fig. 25
$t_{\text{d(on)}}$	Turn-On Delay Time		8				
$t_r$	Rise Time		11				
$t_{\text{d(off)}}$	Turn-Off Delay Time		17				
$t_f$	Fall Time		5		ns	$V_{\text{DD}} = 400 \text{ V}, V_{\text{GS}} = -4 \text{ V}/15 \text{ V}$ $I_D = 13.2 \text{ A}, R_{\text{G(ext)}} = 2.5 \Omega, L = 135 \mu\text{H}$ Timing relative to $V_{\text{DS}}$ Inductive load	Fig. 26
$R_{\text{G(int)}}$	Internal Gate Resistance		3				
$Q_{\text{gs}}$	Gate to Source Charge		13		nC	$V_{\text{DS}} = 400 \text{ V}, V_{\text{GS}} = -4 \text{ V}/15 \text{ V}$ $I_D = 13.2 \text{ A}$ Per IEC60747-8-4 pg 21	Fig. 12
$Q_{\text{gd}}$	Gate to Drain Charge		17				
$Q_g$	Total Gate Charge		46				

Note (1):  $C_{\text{o(er)}}$ , a lumped capacitance that gives same stored energy as  $C_{\text{oss}}$  while  $V_{\text{ds}}$  is rising from 0 to 400V

$C_{\text{o(tr)}}$ , a lumped capacitance that gives same charging time as  $C_{\text{oss}}$  while  $V_{\text{ds}}$  is rising from 0 to 400V

**Reverse Diode Characteristics ( $T_c = 25^\circ\text{C}$  unless otherwise specified)**

Symbol	Parameter	Typ.	Max.	Unit	Test Conditions	Note
$V_{SD}$	Diode Forward Voltage	5.1		V	$V_{GS} = -4 \text{ V}, I_{SD} = 6.6 \text{ A}, T_J = 25^\circ\text{C}$	Fig. 8, 9, 10
		4.8		V	$V_{GS} = -4 \text{ V}, I_{SD} = 6.6 \text{ A}, T_J = 175^\circ\text{C}$	
$I_S$	Continuous Diode Forward Current		23	A	$V_{GS} = -4 \text{ V}, T_c = 25^\circ\text{C}$	
$I_{S,pulse}$	Diode pulse Current		99	A	$V_{GS} = -4 \text{ V}$ , pulse width $t_p$ limited by $T_{jmax}$	
$t_{rr}$	Reverse Recover time	11		ns	$V_{GS} = -4 \text{ V}, I_{SD} = 13.2 \text{ A}, V_R = 400 \text{ V}$ $dif/dt = 4500 \text{ A}/\mu\text{s}, T_J = 175^\circ\text{C}$	
$Q_{rr}$	Reverse Recovery Charge	151		nC		
$I_{rrm}$	Peak Reverse Recovery Current	27		A	$V_{GS} = -4 \text{ V}, I_{SD} = 13.2 \text{ A}, V_R = 400 \text{ V}$ $dif/dt = 2400 \text{ A}/\mu\text{s}, T_J = 175^\circ\text{C}$	
$t_{rr}$	Reverse Recover time	16		ns		
$Q_{rr}$	Reverse Recovery Charge	110		nC		
$I_{rrm}$	Peak Reverse Recovery Current	12		A		

**Thermal Characteristics**

Symbol	Parameter	Typ.	Unit	Test Conditions	Note
$R_{0JC}$	Thermal Resistance from Junction to Case	0.99	°C/W		Fig. 21
$R_{0JA}$	Thermal Resistance From Junction to Ambient	40			

### Typical Performance

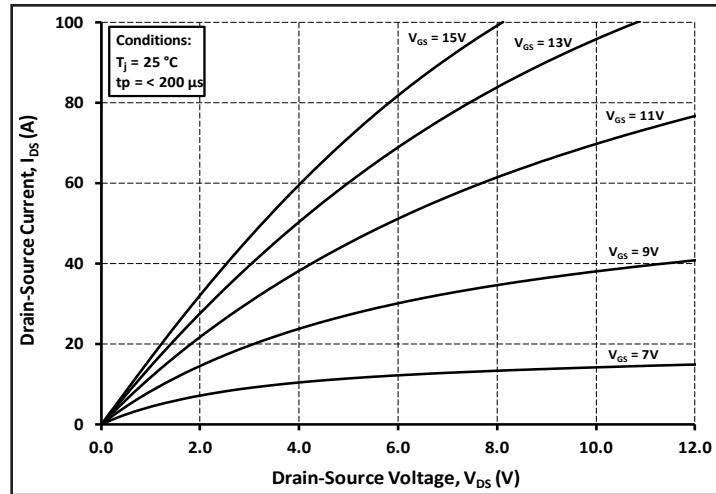
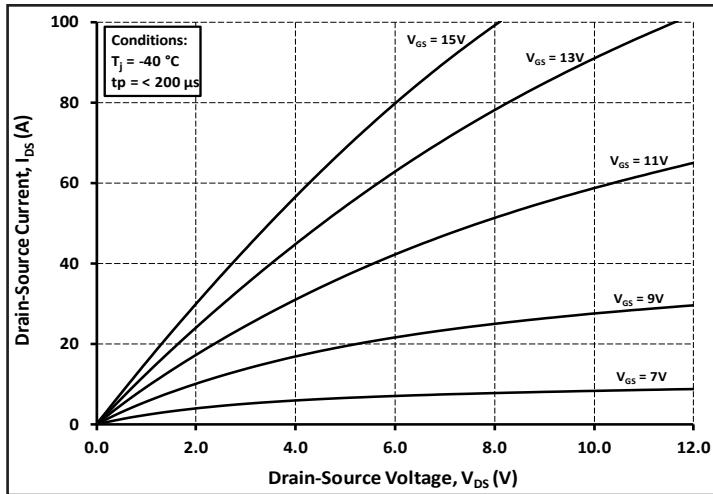


Figure 1. Output Characteristics  $T_J = -40^\circ\text{C}$

Figure 2. Output Characteristics  $T_J = 25^\circ\text{C}$

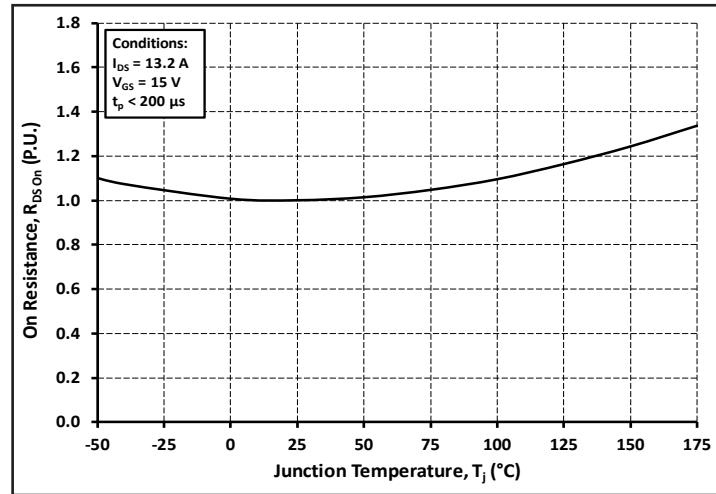
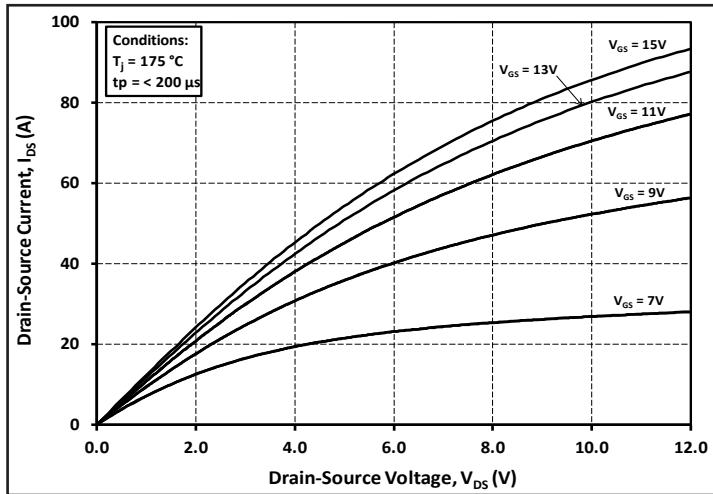


Figure 3. Output Characteristics  $T_J = 175^\circ\text{C}$

Figure 4. Normalized On-Resistance vs. Temperature

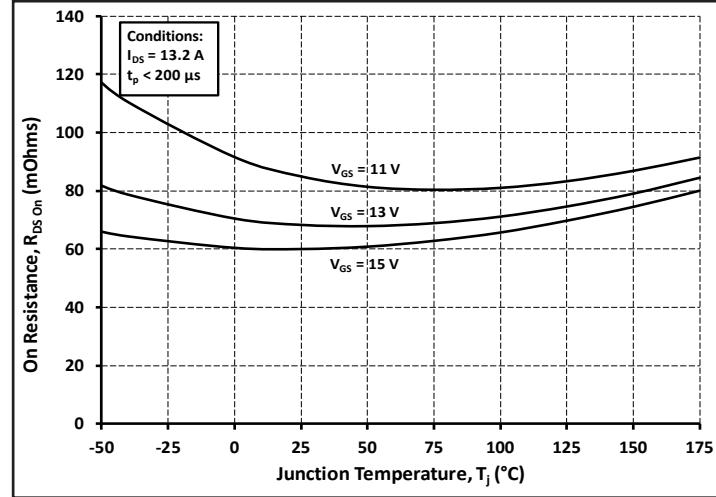
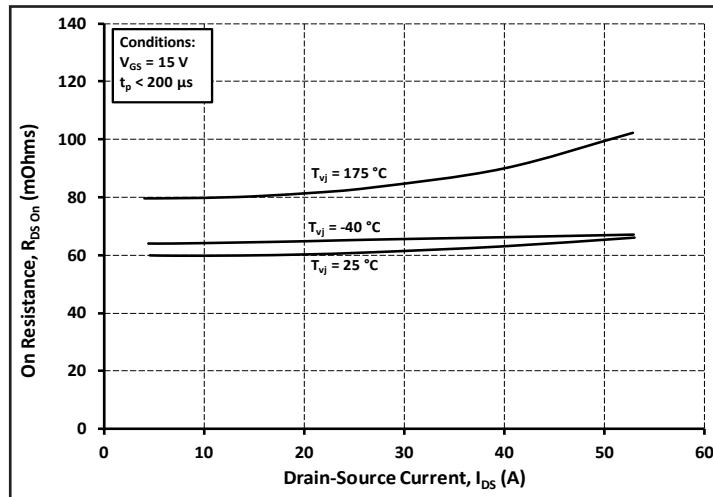


Figure 5. On-Resistance vs. Drain Current For Various Temperatures

Figure 6. On-Resistance vs. Temperature For Various Gate Voltage

### Typical Performance

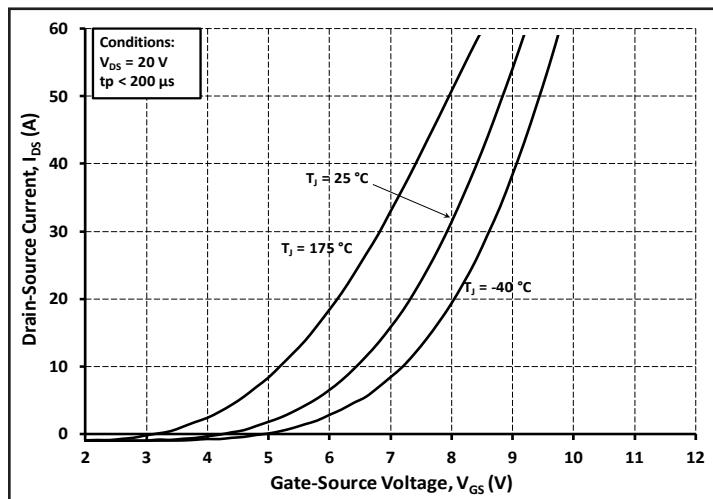


Figure 7. Transfer Characteristic for Various Junction Temperatures

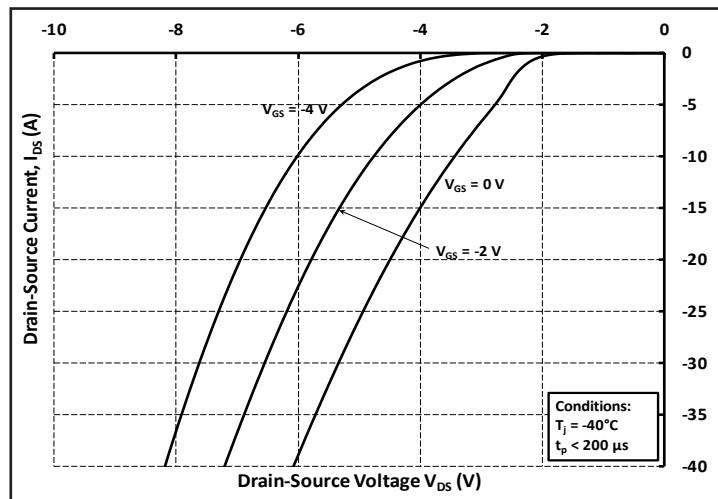


Figure 8. Body Diode Characteristic at  $-40^\circ\text{C}$

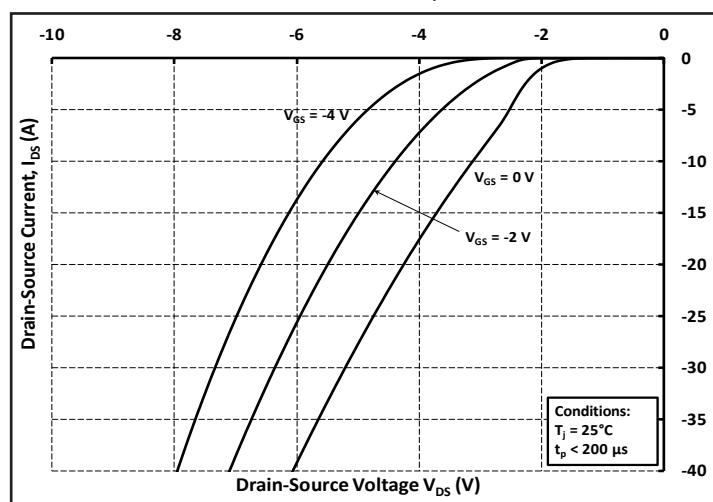


Figure 9. Body Diode Characteristic at  $25^\circ\text{C}$

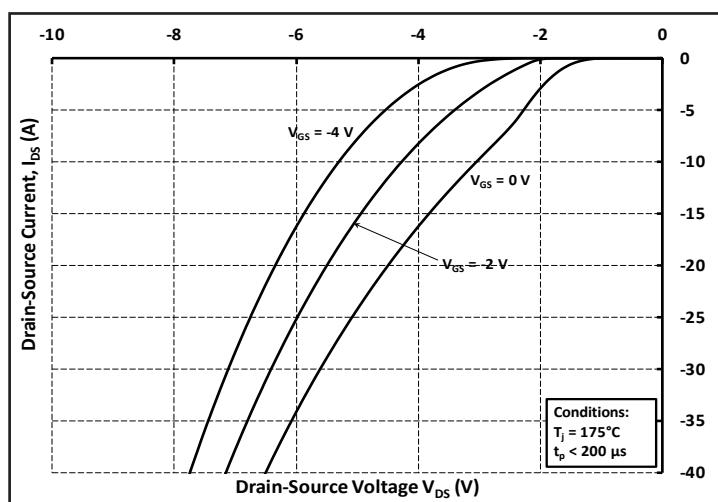


Figure 10. Body Diode Characteristic at  $175^\circ\text{C}$

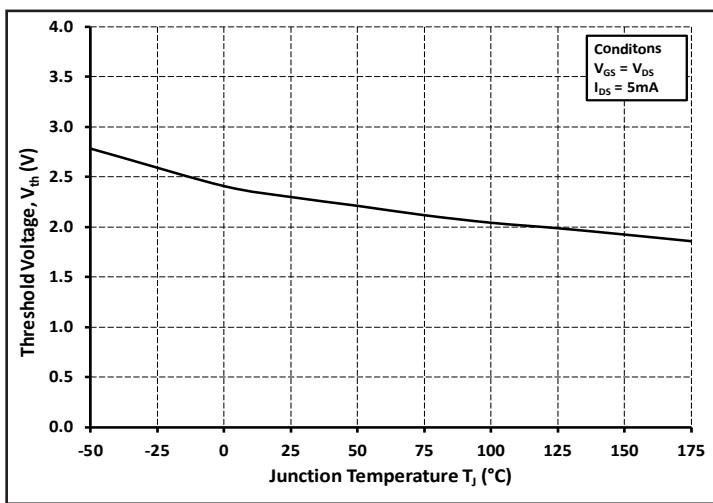


Figure 11. Threshold Voltage vs. Temperature

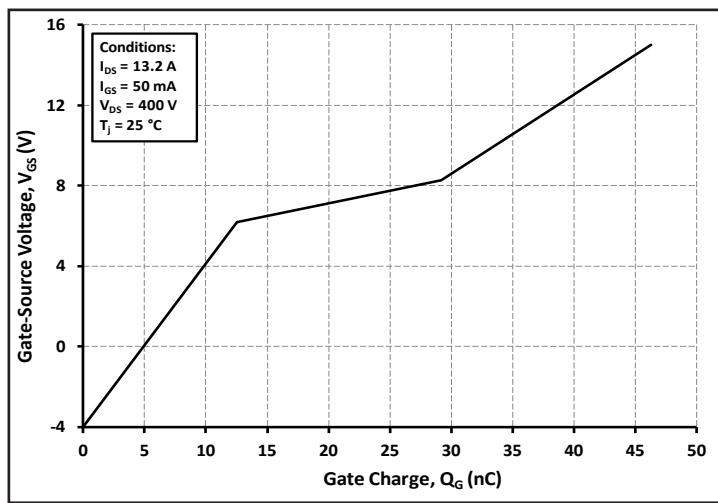


Figure 12. Gate Charge Characteristics

### Typical Performance

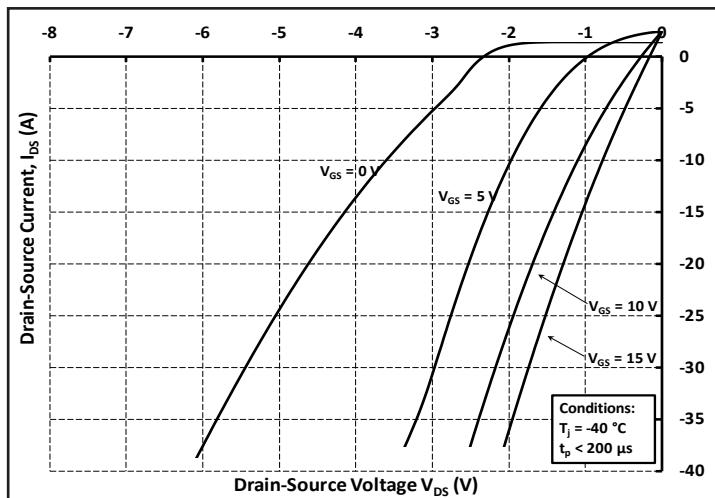


Figure 13. 3rd Quadrant Characteristic at  $-40\text{ }^\circ\text{C}$

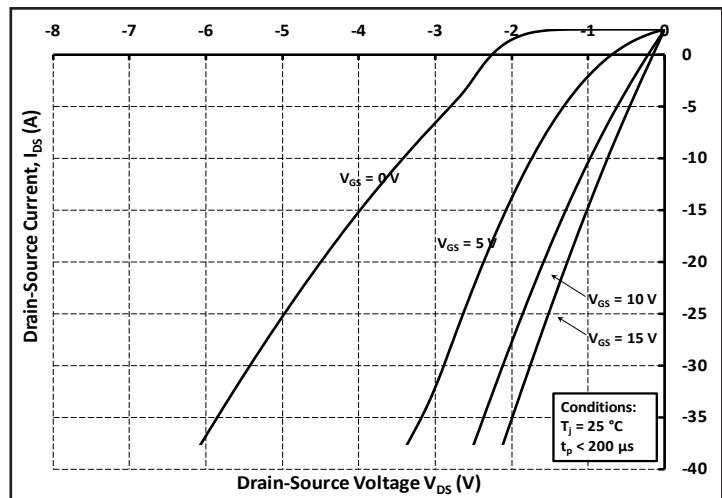


Figure 14. 3rd Quadrant Characteristic at  $25\text{ }^\circ\text{C}$

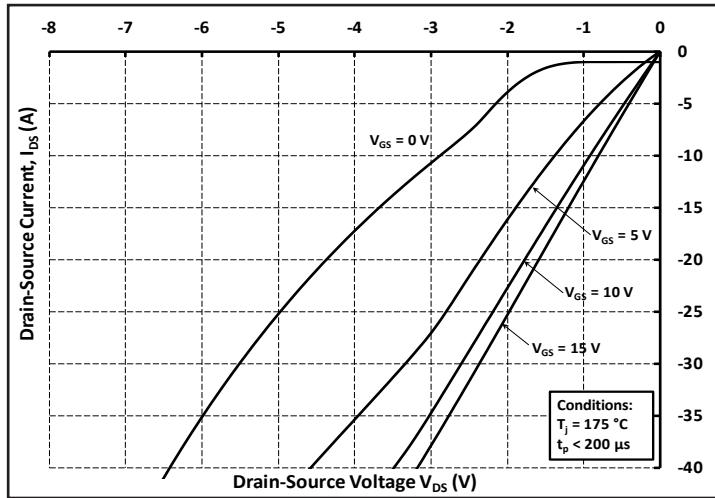


Figure 15. 3rd Quadrant Characteristic at  $175\text{ }^\circ\text{C}$

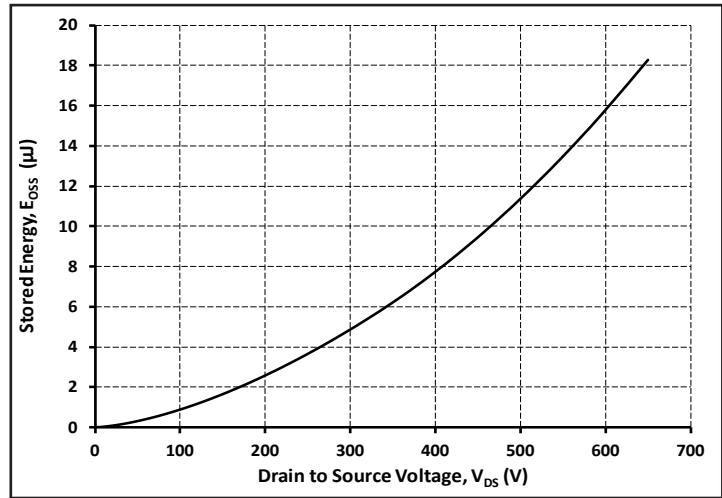


Figure 16. Output Capacitor Stored Energy

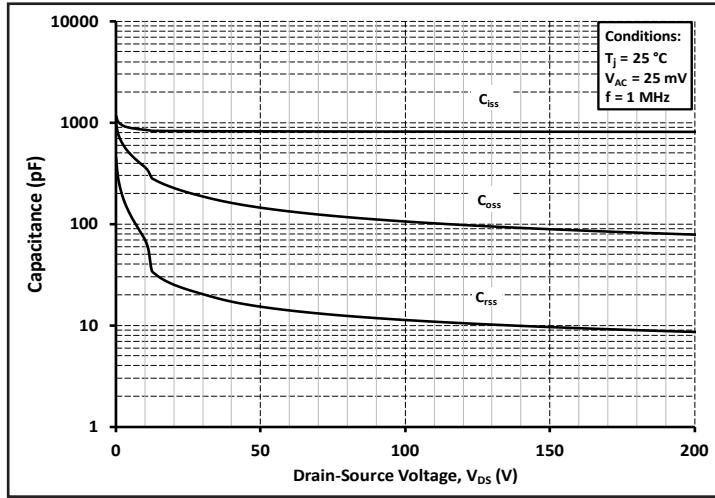


Figure 17. Capacitances vs. Drain-Source Voltage (0 - 200V)

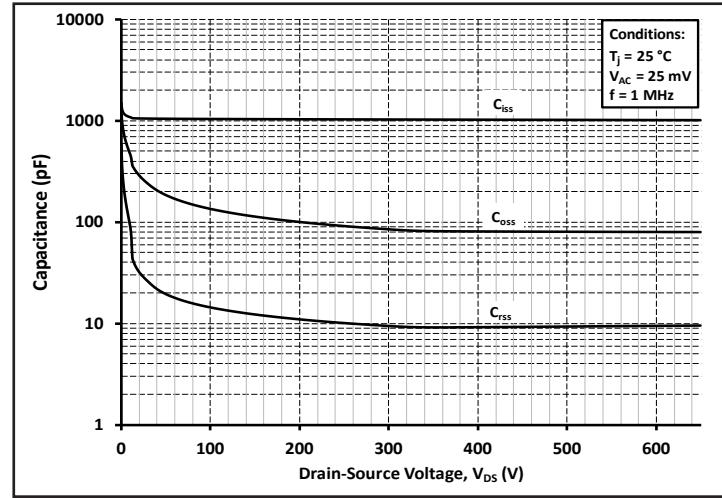


Figure 18. Capacitances vs. Drain-Source Voltage (0 - 650V)

### Typical Performance

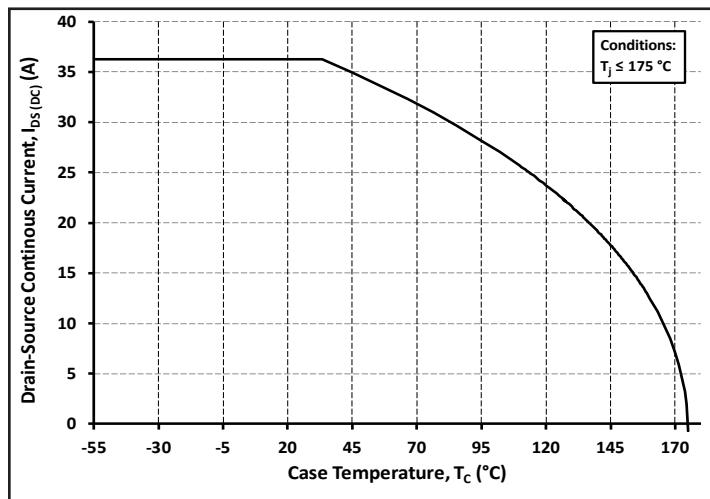


Figure 19. Continuous Drain Current Derating vs. Case Temperature

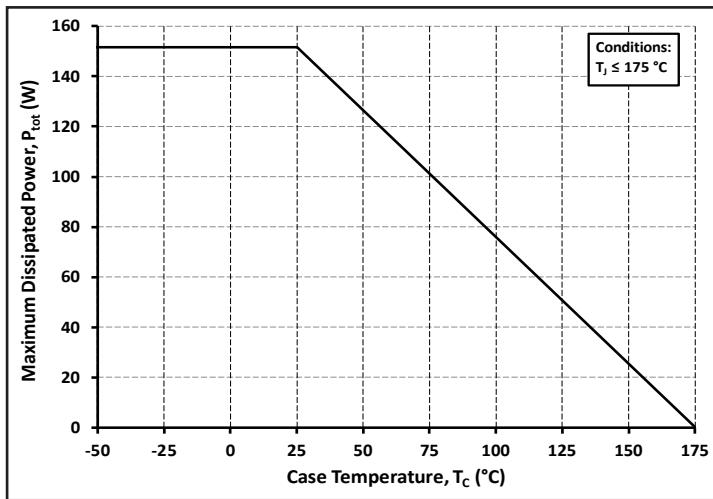


Figure 20. Maximum Power Dissipation Derating Vs. Case Temperature

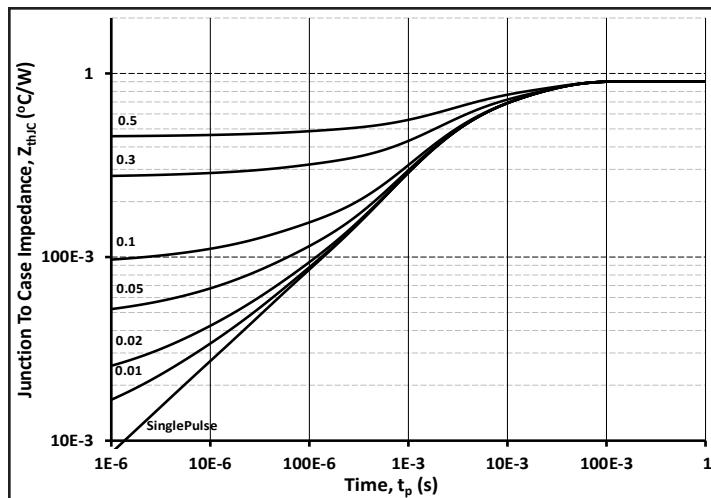


Figure 21. Transient Thermal Impedance (Junction - Case)

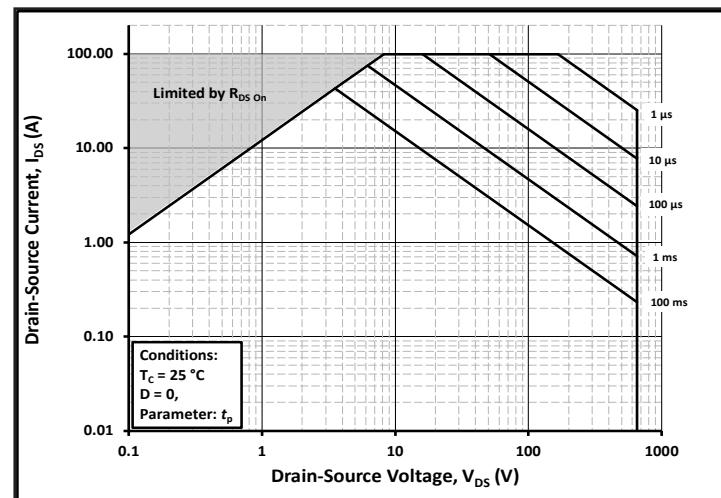


Figure 22. Safe Operating Area

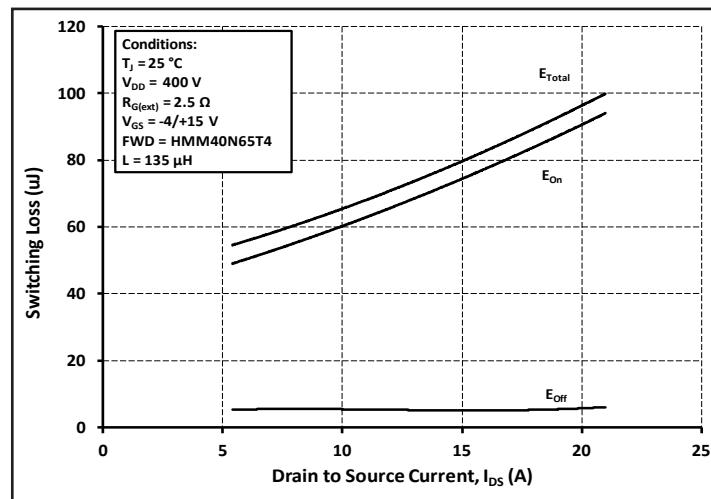


Figure 23. Clamped Inductive Switching Energy vs. Drain Current (V<sub>DD</sub> = 400V)

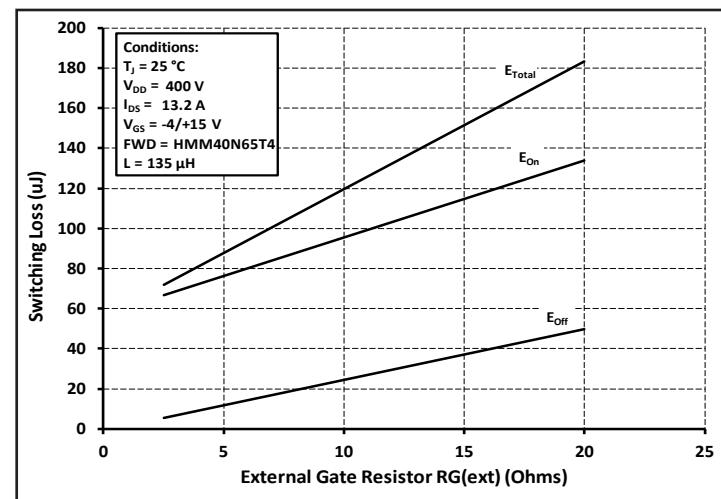


Figure 24. Clamped Inductive Switching Energy vs. R<sub>G(ext)</sub>

### Typical Performance

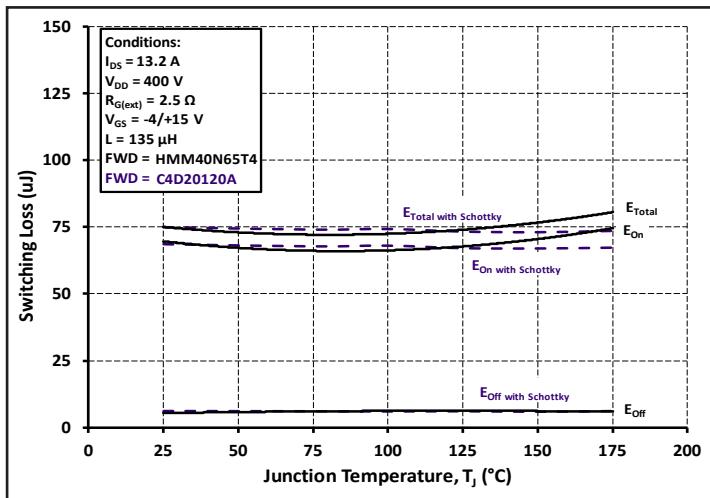


Figure 25. Clamped Inductive Switching Energy vs.  
Temperature

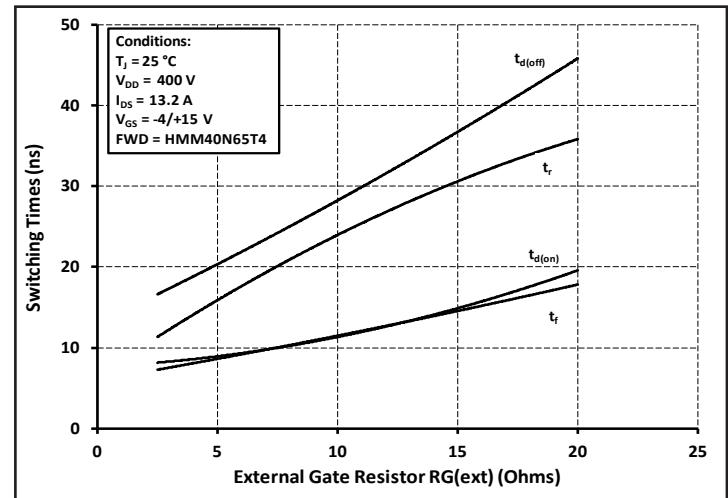


Figure 26. Switching Times vs.  $R_{G(ext)}$

### Test Circuit Schematic

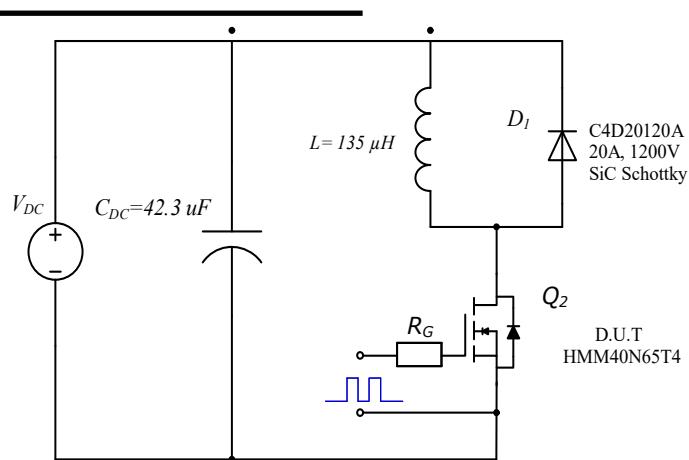


Figure 27. Clamped Inductive Switching Waveform Test Circuit

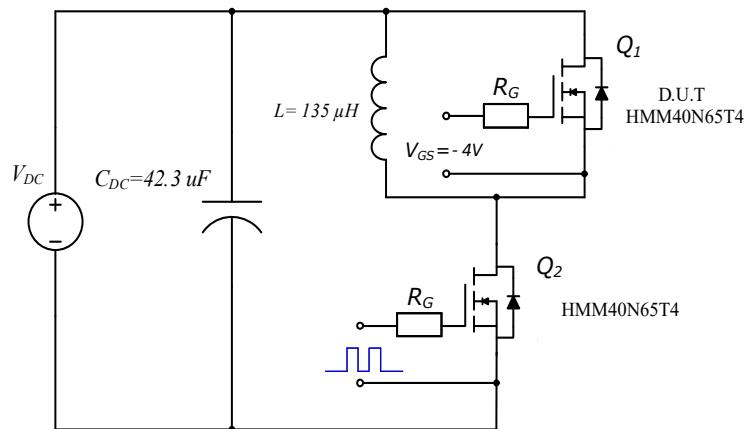


Figure 28. Body Diode Recovery Test Circuit

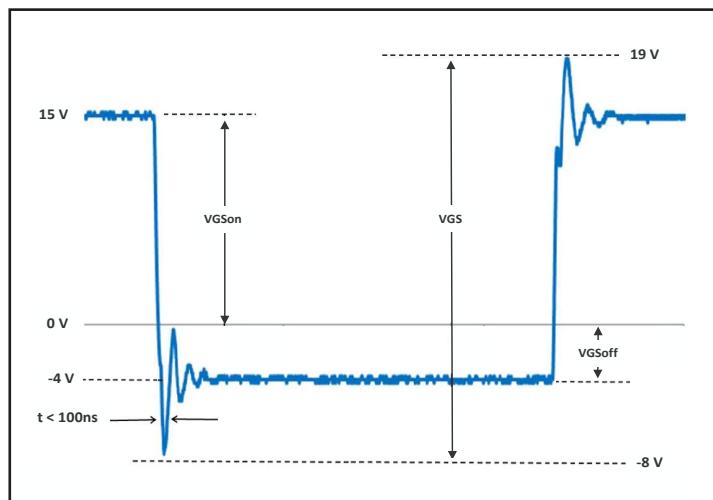
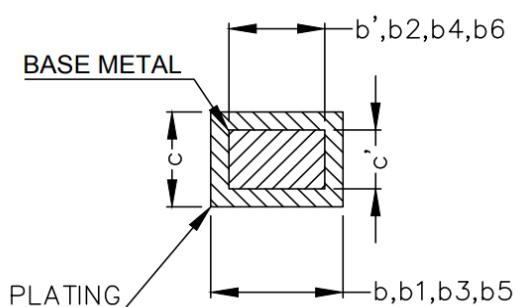
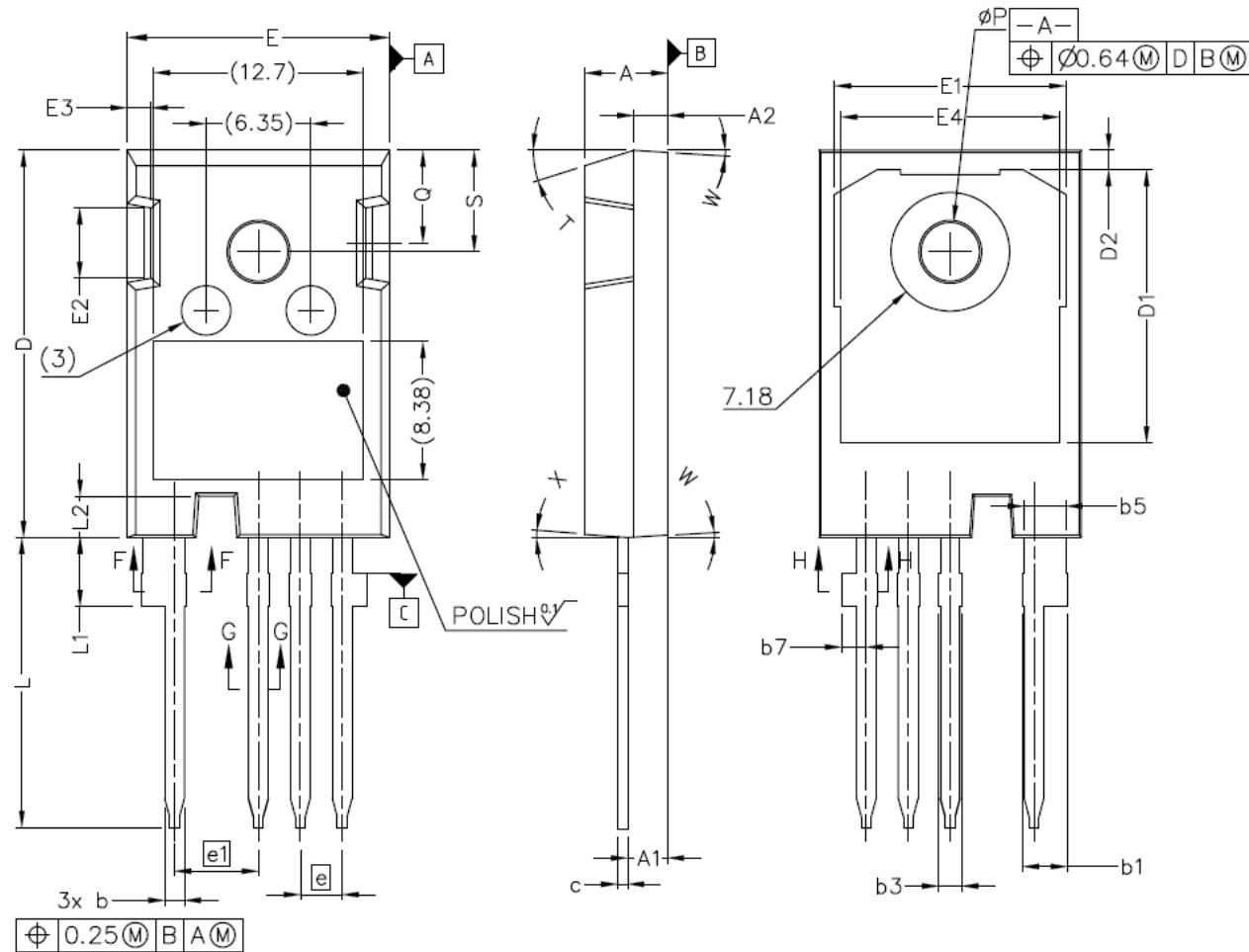


Figure 29.  $V_{GS}$  Waveform Example

### Package Dimensions

Package TO-247-4L



SECTION "F-F", "G-G" AND "H-H"  
SCALE: NONE

### Package Dimensions

Package TO-247-4L

NOTE :

1. ALL METAL SURFACES: TIN PLATED, EXCEPT AREA OF CUT
2. DIMENSIONING & TOLERANCEING CONFIRM TO ASME Y14.5M-1994.
3. ALL DIMENSIONS ARE IN MILLIMETERS.  
ANGLES ARE IN DEGREES.
4. 'N' IS THE NUMBER OF TERMINAL POSITIONS

SYM	MILLIMETERS	
	MIN	MAX
A	4.83	5.21
A1	2.29	2.54
A2	1.91	2.16
b`	1.07	1.28
b	1.07	1.33
b1	2.39	2.94
b2	2.39	2.84
b3	1.07	1.60
b4	1.07	1.50
b5	2.39	2.69
b6	2.39	2.64
b7	1.30	1.70
c`	0.55	0.65
c	0.55	0.68
D	23.30	23.60
D1	16.25	17.65
D2	0.95	1.25
E	15.75	16.13

SYM	MILLIMETERS	
	MIN	MAX
E1	13.10	14.15
E2	3.68	5.10
E3	1.00	1.90
E4	12.38	13.43
e	2.54 BSC	
e1	5.08 BSC	
N*	4	
L	17.31	17.82
L1	3.97	4.37
L2	2.35	2.65
Ø P	3.51	3.65
Q	5.49	6.00
S	6.04	6.30
T	17.5° REF.	
W	3.5° REF.	
X	4° REF.	

